IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Shigeharu YAMAGAMI et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed September 18, 2006

Examiner

SEMICONDUCTOR DEVICE AND METHOD FOR MANUFACTURING SAME

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

September 18, 2006

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

Docket No. 8017-1200

III.	CONCISE EXPLANATION	OF THE RELEVANCE	12 Rec'd PCT/PTO 1 8 SEF	²⁰⁰⁶
	(check at least one	bòx)		

a. DOCUMENTS IN THE ENGLISH LANGUAGE

The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.

b. DOCUMENTS NOT IN THE ENGLISH LANGUAGE

A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:

English abstracts are provided.

An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).

d. OTHER

The following additional information is provided for the Examiner's consideration.

FEES

This Information Disclosure Statement is being filed concurrently with the filing of a new patent application; therefore, no fee is required.

If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned.

YOUNG & THOMPSON

Respectfully submitted,

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Enclosures:	\boxtimes	Form $PTO-1449(s)$
	\boxtimes	Documents
	\boxtimes	Foreign Search Report
		Other:

INFORMATION DISCLOSURE CITATION	ON
IN AN APPLICATION	

(Use several sheets if necessary)

Attorney Docket No.: **8017-1200**

NEW NATIONAL PHASE

Applicant:

Shigeharu YAMAGAMI et al.

Filing Date:

September 18, 2006

Group Art Unit:

U.S. PATENT DOCUMENTS Subclass Filing date Examiner **Document Number** Date Name Class Initial (if appropriate) **FOREIGN PATENT DOCUMENTS** Subclass Translation Class Examiner **Document Number** Date Country Initial Yes No 4/19/2002 **JAPAN** JP 2002-118255 JP 2003-229575 8/15/2003 **JAPAN** JP 2001-298194 10/26/2001 **JAPAN JAPAN** 7/12/1996 JP 8-181323 WIPO WO 2005/022637 3/10/2005 WIPO 4/28/2005 WO 2005/038931 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) **DATE CONSIDERED EXAMINER:**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if

not in conformance and not considered. Include copy of this form with next communication to the applicant.

* English language abstract provided for the Examiner's convenience